

SN5439, SN7439 QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS WITH OPEN-COLLECTOR OUTPUTS

SDLS106 – MAY 1983 – REVISED MARCH 1988

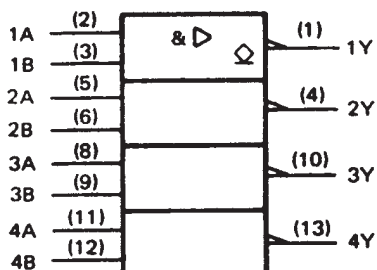
- Current Sinking Capability up to 80 mA
- Guaranteed Fan-Out of 30 Series 54/74 Loads
- Dependable Texas Instruments Quality and Reliability

description

These devices contain four independent 2-input NAND buffers. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher V_{OH} levels.

The SN5439 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN7439 is characterized for operation from 0°C to 70°C .

logic symbol†

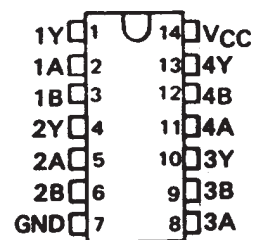


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

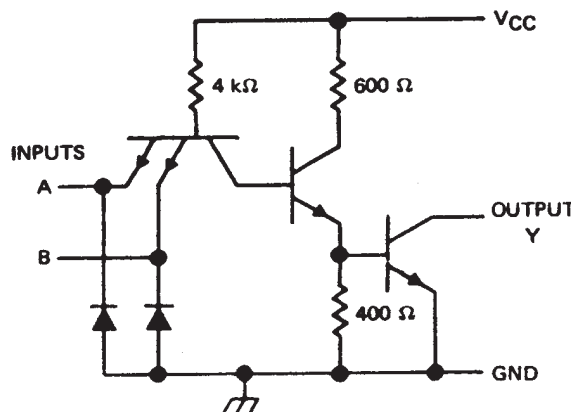
FUNCTION TABLE (each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

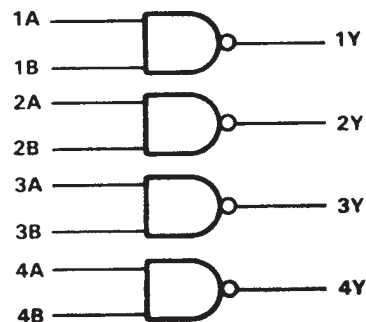
SN5439 . . . J PACKAGE
SN7439 . . . N PACKAGE
(TOP VIEW)



schematics (each gate)



logic diagram



positive logic

$$Y = \overline{A \cdot B} \text{ or } Y = \overline{A} + \overline{B}$$

SN5439, SN7439

QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS

WITH OPEN-COLLECTOR OUTPUTS

SDLS106 – MAY 1983 – REVISED MARCH 1988

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7V
Input voltage	7V
Off-state output voltage	7V
Operating free-air temperature range: SN5439	–55°C to 125°C
SN7439	0°C to 70°C
Storage temperature range	–65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN5439			SN7439			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
V_{OH}	High-level output voltage			5.5			5.5	V
I_{OL}	Low-level output voltage			60			60	mA
							80†	
T_A	Operating free-air temperature	–55		125	0		70	°C

†The extended limit applies only if V_{CC} is maintained between 4.75 and 5.25 V.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5439			SN7439			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	
V_{IK}	$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$			–1.5			–1.5	V
I_{OH}	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, V_{OH} = 5.5 \text{ V}$						0.25	mA
	$V_{CC} = \text{MIN}, V_{IL} = 0.7 \text{ V}, V_{OH} = 5.5 \text{ V}$			0.25				
V_{OL}	$V_{CC} = \text{MIN}, I_{OL} = 48 \text{ mA}$			0.4			0.4	V
	$V_{CC} = \text{MIN}, I_{OL} = 60 \text{ mA}$			0.5			0.5	
	$V_{CC} = 4.75 \text{ V}, I_{OL} = 80 \text{ mA}$						0.6	
I_I	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1			1	mA
I_{IH}	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$			40			40	μA
I_{IL}	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$			–1.6			–1.6	mA
I_{CCH}	$V_{CC} = \text{MAX}, V_I = 0$			54			54	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN5439		SN7439		UNIT
				MIN	MAX	MIN	MAX	
t_{PLH}	A or B	Y	$R_L = 133 \Omega, C_L = 45 \text{ pF}$		22		22	ns
t_{PHL}					18		18	

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.